Advanced AR/VR Technologies and Machine Learning Applications in Smart Environments

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Message from the Guest Editor

VR/AR technology has presented new challenges in many application fields, such as metaverse systems, cyber education, and artificial intelligence. In this special issue, we invite original research papers and review articles that consider VR/AR technology and machine learning systems. New system architectures for VR/AR applications and machine learning systems can be addressed from a systems point of view. Potential topics include, but are not limited, to the following:

- VR/AR applications
- Machine learning system
- New VR/AR applications
- System support for VR/AR systems
- Performance analysis for VR/AR system
- Natural language processing
- Speech recognition system
- Intelligent virtual human/robot system

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Special Issue

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Message from the Editor-in-Chief

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